

STD22NM20N

N-CHANNEL 200V - 0.088Ω - 22A DPAK ULTRA LOW GATE CHARGE MDmesh™ II MOSFET

Table 1: General Features

| TYPE | V _{DSS} | R _{DS(on)} | I _D | |
|------------|------------------|---------------------|----------------|--|
| STD22NM20N | 200 V | < 0.105 Ω | 22 A | |

- WORLDWIDE LOWEST GATE CHARGE
- TYPICAL $R_{DS}(on) = 0.088 \Omega$
- HIGH dv/dt and AVALANCHE CAPABILITIES
- LOW INPUT CAPACITANCE
- LOW GATE RESISTANCE

DESCRIPTION

This 200V MOSFET with a new advanced layout brings all unique advantages of MDmesh technology to lower voltages. The device exhibits worldwide lowest gate charge for any given onresistance. Its use is therefore ideal as primary switch in isolated DC-DC converters for Telecom and Computer applications. Used in combination with secondary-side low-voltage STripFET™ products, it contributes to reducting losses and boosting effeciency.

APPLICATIONS

The MDmesh[™] family is very suitable for increasing power density allowing system miniaturization and higher efficiencies

Figure 1: Package

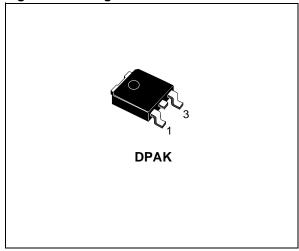


Figure 2: Internal Schematic Diagram

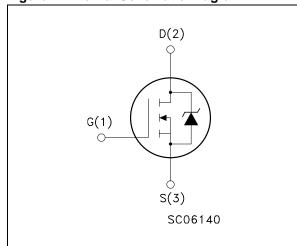


Table 2: Order Codes

| SALES TYPE | SALES TYPE MARKING | | PACKAGING | |
|--------------|-----------------------|--|-------------|--|
| STD22NM20NT4 | STD22NM20NT4 D22NM20N | | TAPE & REEL | |

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Table 3: Absolute Maximum ratings

| Symbol | Parameter | Value | Unit |
|------------------------------------|---|-------------------|----------|
| V _{DS} | Drain-source Voltage (V _{GS} = 0) | 200 | V |
| V_{DGR} | Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$) | 200 | V |
| V _{GS} | Gate- source Voltage | ± 20 | V |
| Ι _D | Drain Current (continuous) at $T_C = 25^\circ$ Drain Current (continuous) at $T_C = 100^\circ$ | 22 13.7 | A A |
| I _{DM} (*) | Drain Current (pulsed) | 88 | А |
| P _{TOT} | Total Dissipation at T _C = 25°C | 100 | W |
| | Derating Factor | 0.8 | W/°C |
| dv/dt (2) | Peak Diode Recovery voltage slope | 14 | V/ns |
| T _j T _{stg} | Storage Temperature Max Operating Junction Temperature | 150 -65 to 150 | °C °C |

^(*) $I_{SD} \le 22A$, $di/dt \le 400A/\mu s$, $V_{DD} = 80\% \ V_{(BR)DSS}$

Table 4: Thermal Data

| Rthj-case | Thermal Resistance Junction-case Max | 1.25 | °C/W |
|------------------------|--|-----------|------|
| Rthj-amb | Thermal Resistance Junction-ambient Max | 100 | °C/W |
| Rthj-ambT _l | Thermal Resistance Junction-pcb (*) Maximum Lead Temperature For Soldering Purpose | 43 275 | °C/W |

^(*) When mounted on 1 inch² FR-4 board, 2 oz Cu, t ≤ 10 sec

Table 5: Avalanche Characteristics

| Symbol | Parameter | Max Value | Unit |
|-----------------|---|-----------|------|
| I _{AS} | Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T _j max) | 22 | A |
| E _{AS} | Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = 22$ A, $V_{DD} = 50$ V) | 380 | mJ |

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ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED)

Table 6: On/Off

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|----------------------|--|---|------|-------|---------|----------|
| V _{(BR)DSS} | Drain-source Breakdown Voltage | $I_D = 1$ mA, $V_{GS} = 0$ | 200 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current (V _{GS} = 0) | V_{DS} = Max Rating V_{DS} = Max Rating, T_{C} = 125 °C | | | 1 10 | μA μA |
| I _{GSS} | Gate-body Leakage Current (V _{DS} = 0) | V _{GS} = ± 20V | | | 100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$ | 3.5 | 4.2 | 5 | V |
| R _{DS(on)} | Static Drain-source On Resistance | V _{GS} = 10V, I _D = 11 A | | 0.088 | 0.105 | Ω |

Table 7: Dynamic

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|---|---|--|------|----------------------|------|----------------------|
| g _{fs} (2) | Forward Transconductance | V _{DS} = 15 V _, I _D =11 A | | 8 | | S |
| C _{iss} C _{oss} C _{rss} | Input Capacitance Output Capacitance Reverse Transfer Capacitance | $V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$ | | 800 330 130 | | pF pF pF |
| Coss eq. (**) | Equivalent Output Capacitiance | V _{GS} = 0 V, V _{DS} = 0 V to 400 V | | 225 | | pF |
| R _G | Gate Input Resistance | f= 1MHz Gate DC Bias = 0 Test Sgnal Level = 20 mV Open Drain | | 5 | | Ω |
| $\begin{array}{c} t_{\text{d(on)}} \\ t_{\text{r}} \\ t_{\text{r(Voff)}} \\ t_{\text{f}} \end{array}$ | Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time | $V_{DD} = 100 \text{ V}, I_{D} = 11 \text{ A}$ $R_{G} = 4.7\Omega \text{ V}_{GS} = 10 \text{ V}$ (see Figure 15) | | 40 15 40 11 | | ns ns ns ns |
| Q _g Q _{gs} Q _{gd} | Total Gate Charge Gate-Source Charge Gate-Drain Charge | $V_{DD} = 100 \text{ V}, I_{D} = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see Figure 19) | | 32 6 25 | 50 | nC nC nC |

^(**) Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDS increases from 0 to 80% VDSS

Table 8: Source Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|-------------------|----------|---------------|
| I _{SD} I _{SDM} (1) | Source-drain Current Source-drain Current (pulsed) | | | | 22 88 | A A |
| V _{SD} (2) | Forward On Voltage | I _{SD} = 20 A, V _{GS} = 0 | | | 1.3 | V |
| t _{rr} Q _{rr} I _{RRM} | Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current | I_{SD} = 20 A, di/dt = 100 A/µs V_{DD} = 100V, T_j = 25°C (see test circuit, Figure 17) | | 160 960 128 | | ns μC A |
| t _{rr} Q _{rr} I _{RRM} | Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current | I_{SD} = 20 A, di/dt = 100 A/µs V_{DD} = 100V, T_j = 150°C (see test circuit, Figure 17) | | 225 1642 15 | | ns μC A |

⁽¹⁾ Pulse width limited by safe operating area.(2) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

Figure 3: Safe Operating Area

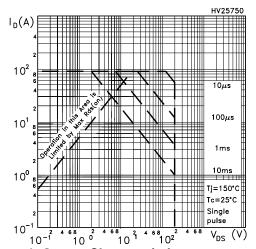


Figure 4: Output Characteristics

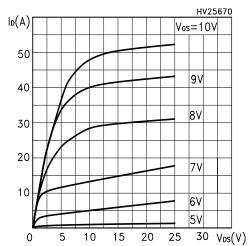


Figure 5: Transconductance

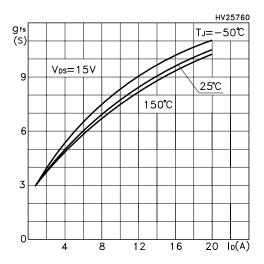


Figure 6: Thermal Impedance

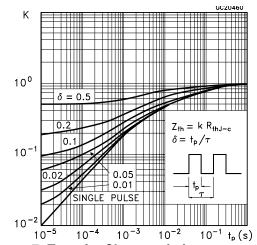


Figure 7: Transfer Characteristics

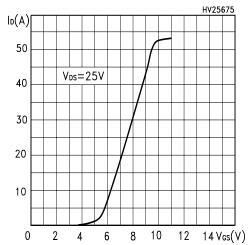
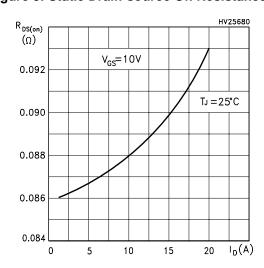


Figure 8: Static Drain-source On Resistance



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Figure 9: Gate Charge vs Gate-source Voltage

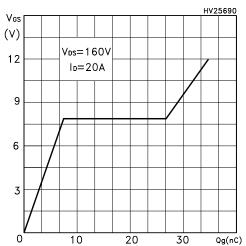


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

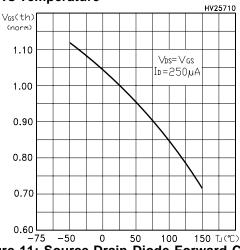


Figure 11: Source-Drain Diode Forward Characteristics

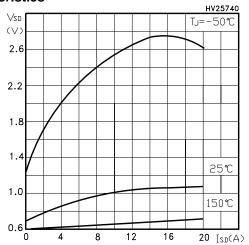


Figure 12: Capacitance Variations

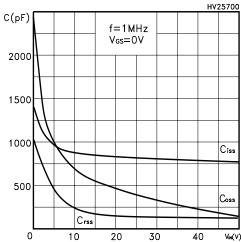


Figure 13: Normalized On Resistance vs Temperature

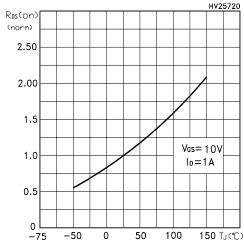


Figure 14: Normalized BVdss vs Temperature

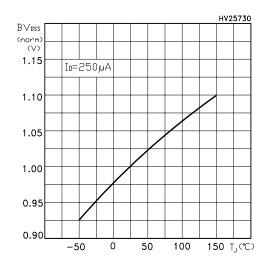


Figure 15: Unclamped Inductive Load Test Circuit

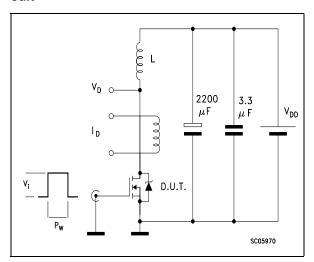


Figure 16: Switching Times Test Circuit For Resistive Load

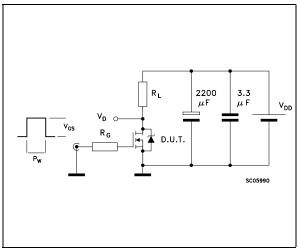


Figure 17: Test Circuit For Inductive Load Switching and Diode Recovery Times

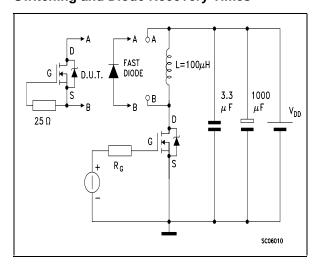


Figure 18: Unclamped Inductive Wafeform

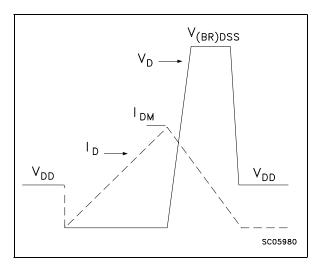
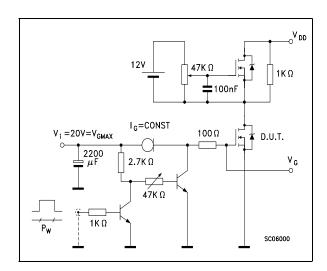
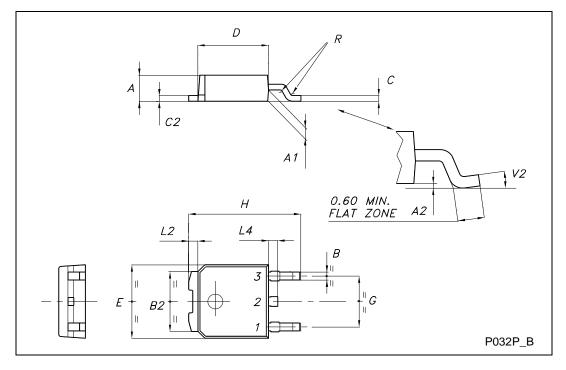


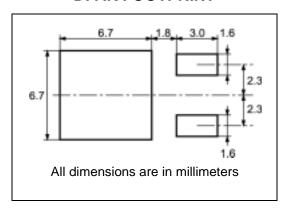
Figure 19: Gate Charge Test Circuit



| DIM. | | mm | | | inch | |
|-------|------|------|-------|-------|-------|-------|
| DIWI. | MIN. | TYP. | MAX. | MIN. | TYP. | MAX. |
| А | 2.20 | | 2.40 | 0.087 | | 0.094 |
| A1 | 0.90 | | 1.10 | 0.035 | | 0.043 |
| A2 | 0.03 | | 0.23 | 0.001 | | 0.009 |
| В | 0.64 | | 0.90 | 0.025 | | 0.035 |
| B2 | 5.20 | | 5.40 | 0.204 | | 0.213 |
| С | 0.45 | | 0.60 | 0.018 | | 0.024 |
| C2 | 0.48 | | 0.60 | 0.019 | | 0.024 |
| D | 6.00 | | 6.20 | 0.236 | | 0.244 |
| Е | 6.40 | | 6.60 | 0.252 | | 0.260 |
| G | 4.40 | | 4.60 | 0.173 | | 0.181 |
| Н | 9.35 | | 10.10 | 0.368 | | 0.398 |
| L2 | | 0.8 | | | 0.031 | |
| L4 | 0.60 | | 1.00 | 0.024 | | 0.039 |
| V2 | 0° | | 8° | 0° | | 0° |



DPAK FOOTPRINT



TAPE AND REEL SHIPMENT

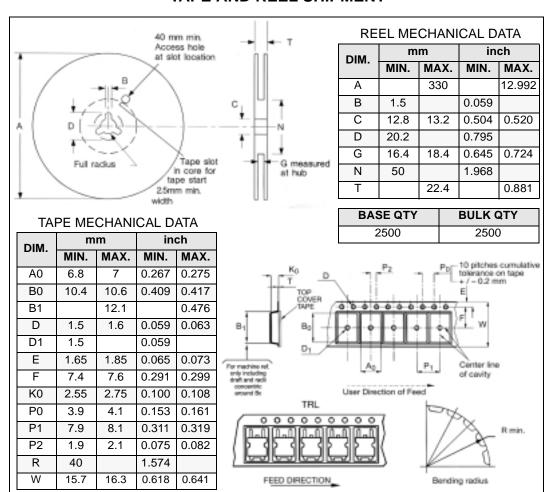


Table 9: Revision History

| Date | Revision | Description of Changes |
|-------------|----------|------------------------|
| 31-May-2004 | 1 | First Release. |
| 15-Mar-2005 | 2 | Update version. |
| 09-May-2005 | 3 | Complete version. |
| 09-Jun-2005 | 4 | New update |

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